


<b>Search Notes</b>  	<b>Application/Control No.</b>  10628261	<b>Applicant(s)/Patent Under Reexamination</b>  KITAMURA, MAMORU
	<b>Examiner</b>  Lee, Siu M	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
375	238, 239, 237, 240, 241, 242, 353, 316	10/4/2006	Siu M. lee
330	251, 253, 259, 260, 264, 265, 269, 271, 277, 270	10/4/2006	Siu M. Lee
327	31, 172	10/4/2006	Siu M. Lee
329	312	10/4/2006	Siu M. Lee
398	191	10/4/2006	Siu M. Lee
323		10/4/2006	Siu M. Lee

SEARCH NOTES		
Search Notes	Date	Examiner
	10/4/2006	Siu M. Lee
US-PGPUB	10/4/2006	Siu M. Lee
USPAT	10/4/2006	Siu M. Lee
USOCR	10/4/2006	Siu M. Lee
EPO	10/4/2006	Siu M. Lee
JPO	10/4/2006	Siu M. Lee
DERWENT	10/4/2006	Siu M. Lee
IEEE	10/4/2006	Siu M. Lee
GOOGLE	10/4/2006	Siu M. Lee
Discuss the application with Chieh Fan	10/11/2006	Siu M. Lee
Update search in EAST	11/20/2006	Siu M. Lee

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
375	238, 353, 237, 239, 240, 241, 242, 316	12/5/2006	Siu M. Lee